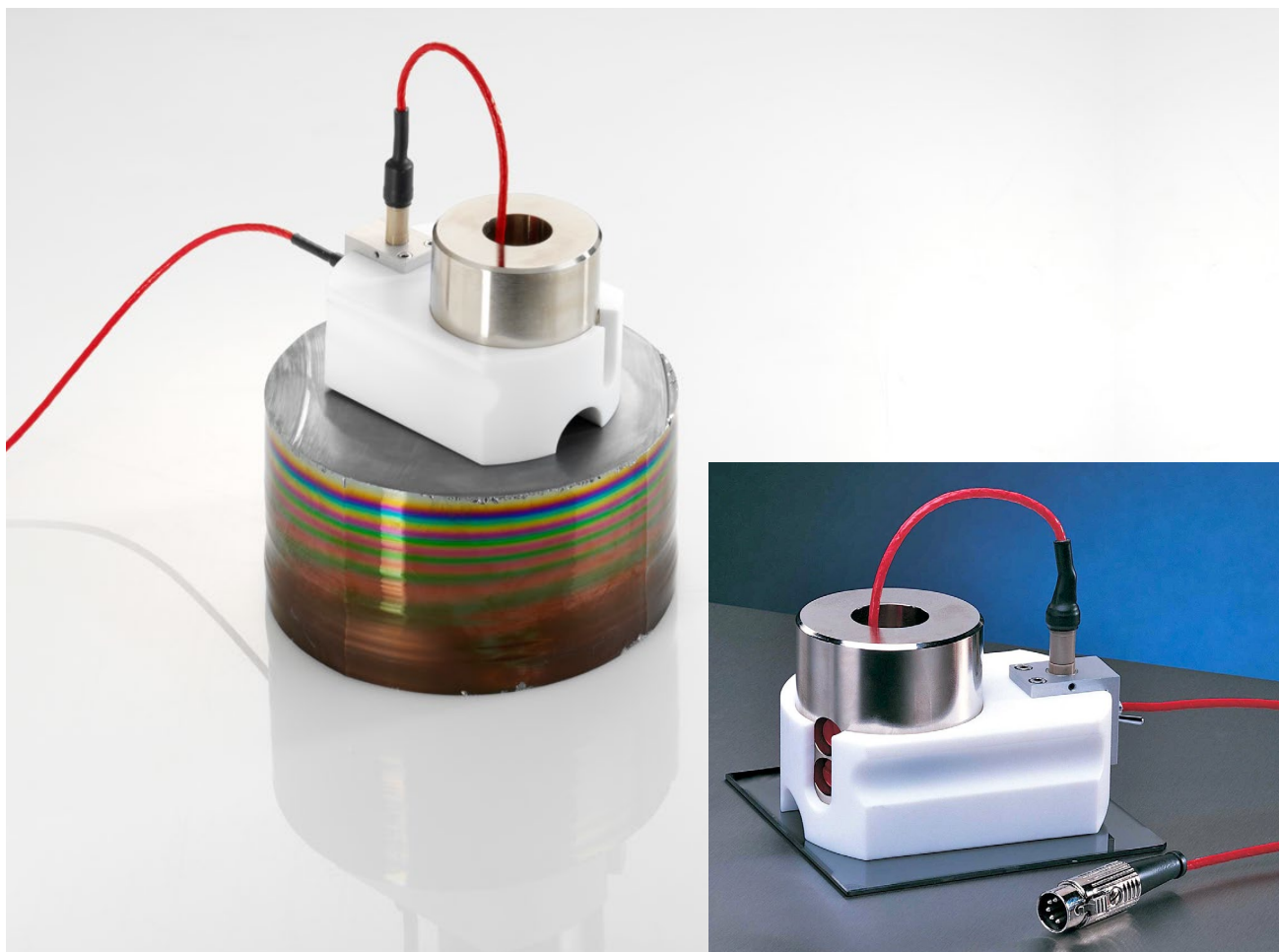


Jandel Engineering Limited



Jandel Hand Applied Probe

Jandel Engineering Limited offers the Hand Applied Probe as a solution for making measurements where portability is a key factor. The system can be used for measuring a wide variety of samples, from thin layers and wafers, up to large ingots. The probe head can have loads of up to 200g per needle and the Hand Applied Probe has a large downward force of around 1.2kg. This measurement solution is therefore not suitable for fragile unsupported samples. As a scale for size, the main image above shows the Hand Applied Probe sitting on top of a 150mm silicon ingot.

Max. sample size	Any reasonable size sample can be measured as long as the Hand Applied Probe can be placed appropriately
Max. sample thickness	Any thickness of sample can be measured as long as the Hand Applied Probe can be placed appropriately
Toggle switch	Prevents current flow when probe is not in contact with sample
Manual placement	Probe is designed to be placed and left while measurement is made to avoid fluctuation associated with handheld measurement
Simple set up	Single wire connects the Hand Applied Probe and measurement electronics

Note: Our Hand Applied Probe solution includes a cylindrical four point probe head. For more information on cylindrical probe heads and the specifications available, please see our cylindrical probe head datasheet.



If you require any further information on the Jandel Hand Applied Probe, please do not hesitate to contact us using the details below.